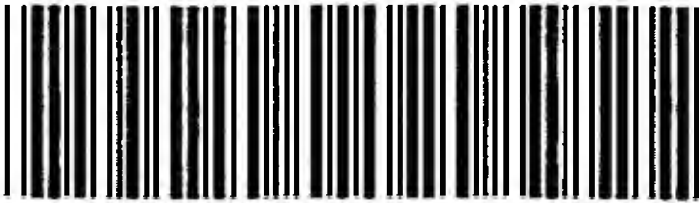


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/542,577	UCHIDA ET AL.	
	Examiner	Art Unit	
	Taeyoon Kim	1651	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Same search as 10/534,715 (EAST search; USPG- pub;USPAT;USOCR;EPO;JPO;Derwe nt)	8/4/2006	TK
Inventor search (same as 10/534,715)	8/4/2006	TK
Inventor search (update)	8/23/2006	TK